

Resource Summary Report

Generated by [NIF](#) on Sep 16, 2026

FEI: Phenom ProX SEM

RRID:SCR_019898

Type: Tool

Proper Citation

FEI: Phenom ProX SEM (RRID:SCR_019898)

Resource Information

URL: <https://www.fei.com/products/sem/phenom-prox/>

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Description: Desktop scanning electron microscope that offers fast, high-resolution imaging in addition to an integrated energy-dispersive X-ray diffraction (EDS) detector for elemental analysis.

Resource Type: instrument resource

Keywords: FEI, SEM, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Phenom ProX SEM

Resource ID: SCR_019898

Alternate IDs: Model_Number_Phenom_ProX

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260912T195924+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Phenom ProX SEM.

No alerts have been found for FEI: Phenom ProX SEM.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.